

<b>Notice of References Cited</b>	Application/Control No. 10/653,215		Applicant(s)/Patent Under Reexamination KIM, JIN-HYUNG	
	Examiner IRIANA CRUZ		Art Unit 2625	Page 1 of 1

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#### NON-PATENT DOCUMENTS

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	U	The IEEE Standard Dictionary of Electrical and Electronic Terms, IEEE, Sixth Edition, Page 1116
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